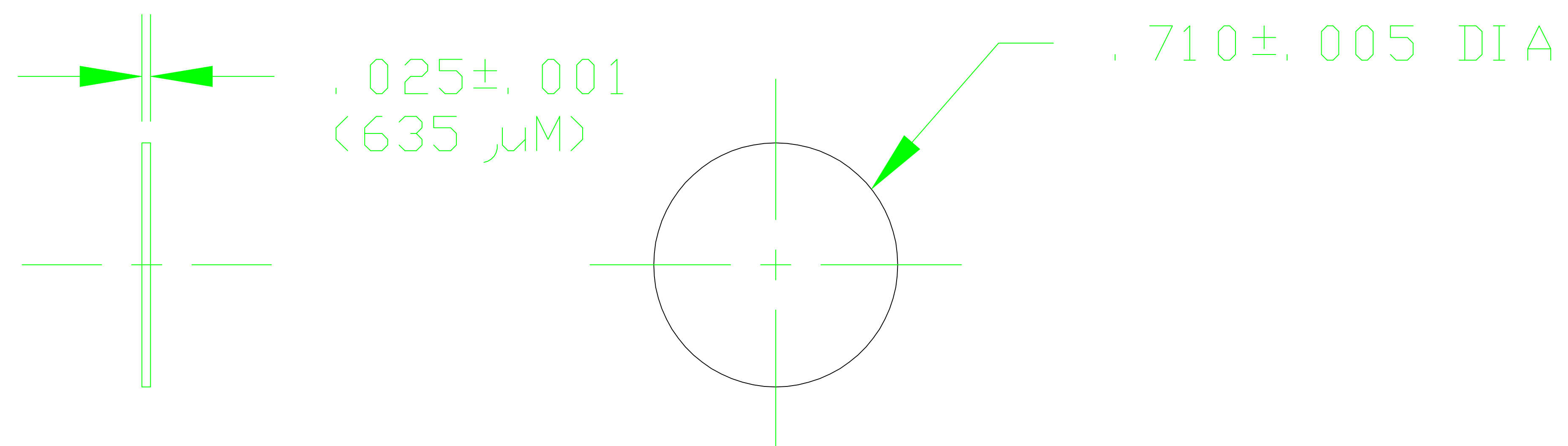


REV.	DATE	DESCRIPTION	BY	APP'D
1	10-88	REVISED NOTE 2	URI BE	



NOTES

1. MATERIAL: GALLIUM ARSENIDE

SPEC FOR:

ETCH PIT DENSITY (EPD) $\leq 1^40 / \text{CM}^2$

ZINC DOPED BETWEEN 2×10^8 AND $2 \times 10^9 / \text{CM}^3$

RECOMMENDED VENDOR:

LASER DIODES INC.

1130 SOMERSET ST.

NEW BRUNSWICK, NJ 08901

<201>249-7000

2. CUT SO FACE OF DISK IS ORIENTED
AT 2° OFF THE 100 AXISTOWARDS THE 111A PLANE

3. POLISH ONE FACE, ETCH THE OTHER

SLAC: PF795-649-48

DRAWN BY SPESE	NUCLEAR PHYSICS LABORATORY UNIVERSITY OF ILLINOIS AT URBANA-CHAMPAIGN	GALLIUM ARSENIDE WAFER		
CHECKED BY	<u>UNLESS OTHERWISE SPECIFIED</u>	PART NO.	SCALE 2=1	FILE 12
APPROVED BY	DIMENSIONS IN INCHES 2 PLACE DEC. \pm .01 BREAK SHARP CORNERS 3 PLACES DEC. \pm .003 FRACTIONAL $\pm 1/32'$ ANGULAR $\pm 0'30'$	NO. REQ'D.	DATE 7-11-88	DWG. NO. C-2709-10
		CHASSIS NO. OR MATERIAL LISTED		